



Project Number:		Tracking Code: TC0720--1352	
Requested by: Jeff Schreck		Date: 5/16/2007	Product Rev: B
Part #: HFHM2-020-T-05.00-DP		Lot #: TBD	Tech: Troy Cook Eng: Troy Cook
Part description: HFHM2-DP			Qty to test: 2
Test Start: 05/16/2007	Test Completed: 7/27/2007		

Current Carrying Capacity Report

PART DESCRIPTION

HFHM2-020-T-05.00-DP

Mated with QSH-DP/QTH-DP

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

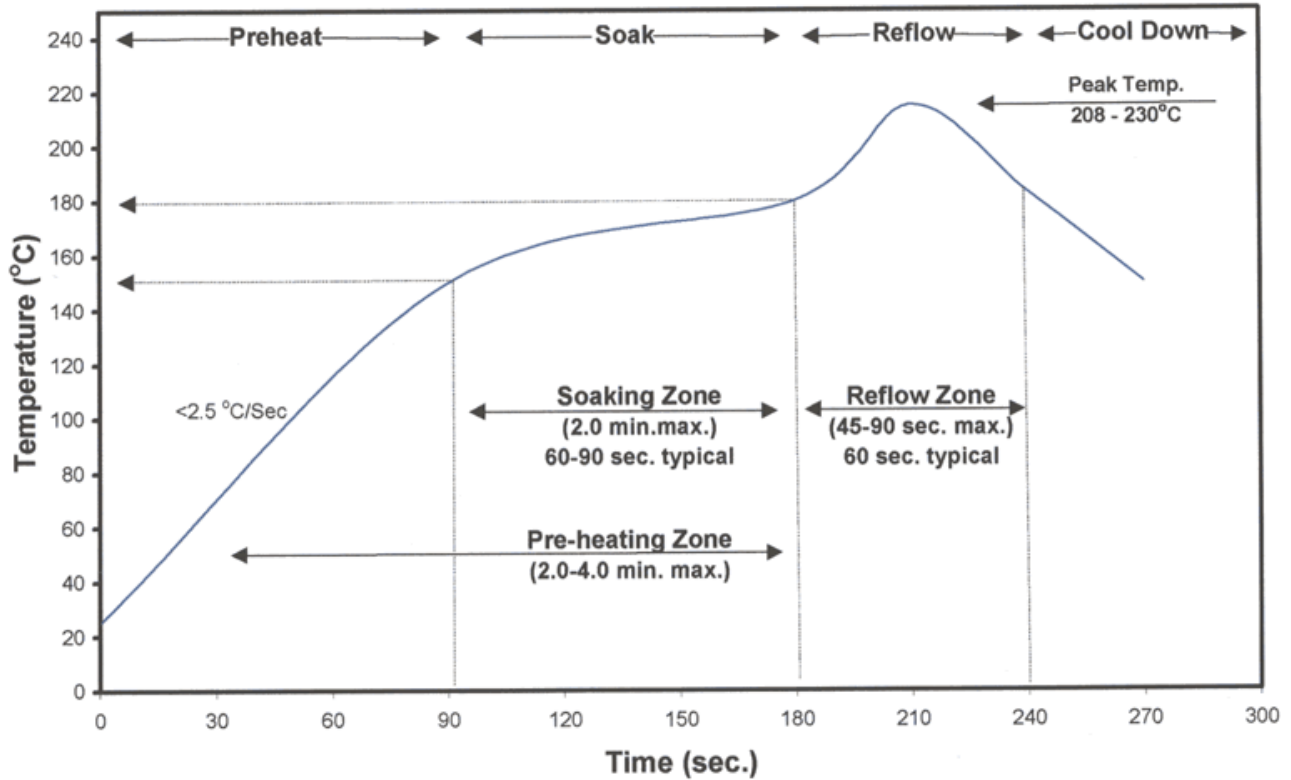
To perform the following tests: CCC

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-100800-TST-XX

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)**Standard Solder Paste Reflow Profile
for Kester Paste Containing
Alloys: Sn63Pb37 or Sn62Pb36Ag02**

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

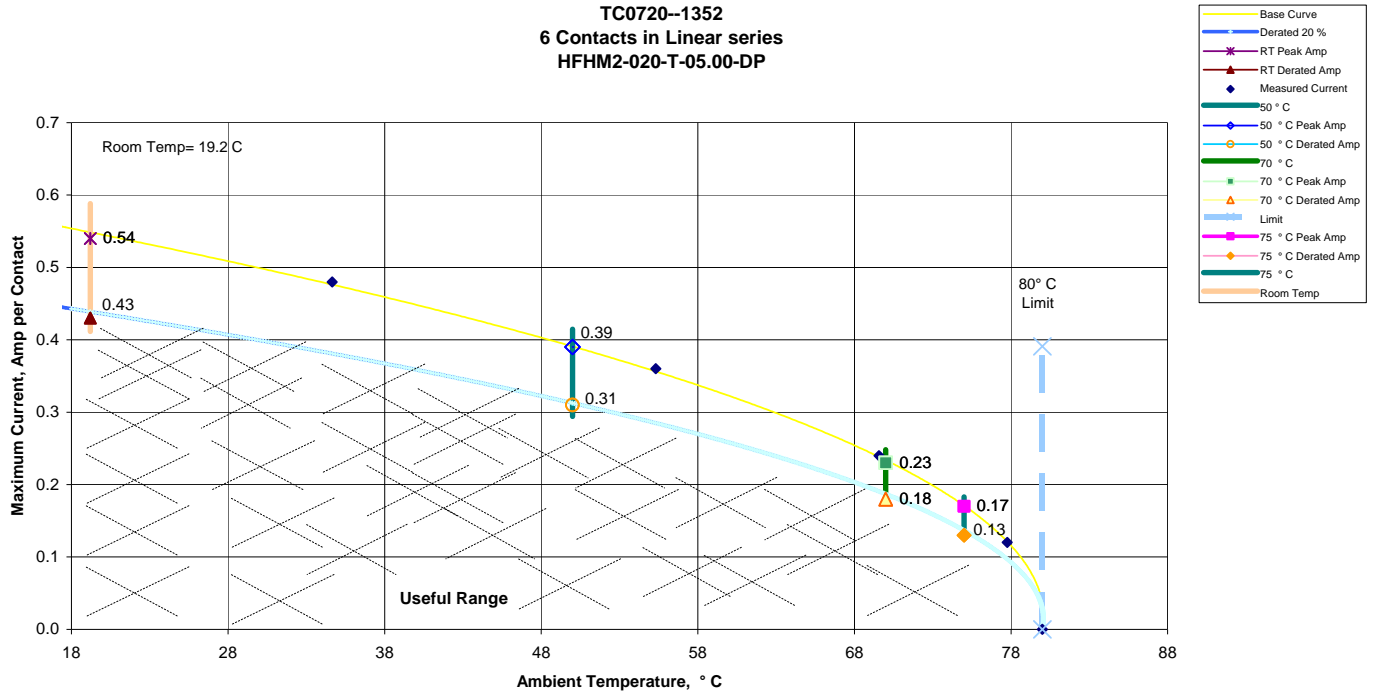
TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
 - a. Self heating (resistive)
 - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at three temperature points are reported:
 - a. Ambient
 - b. 50° C
 - c. 70° C
 - d. 80° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

RESULTS

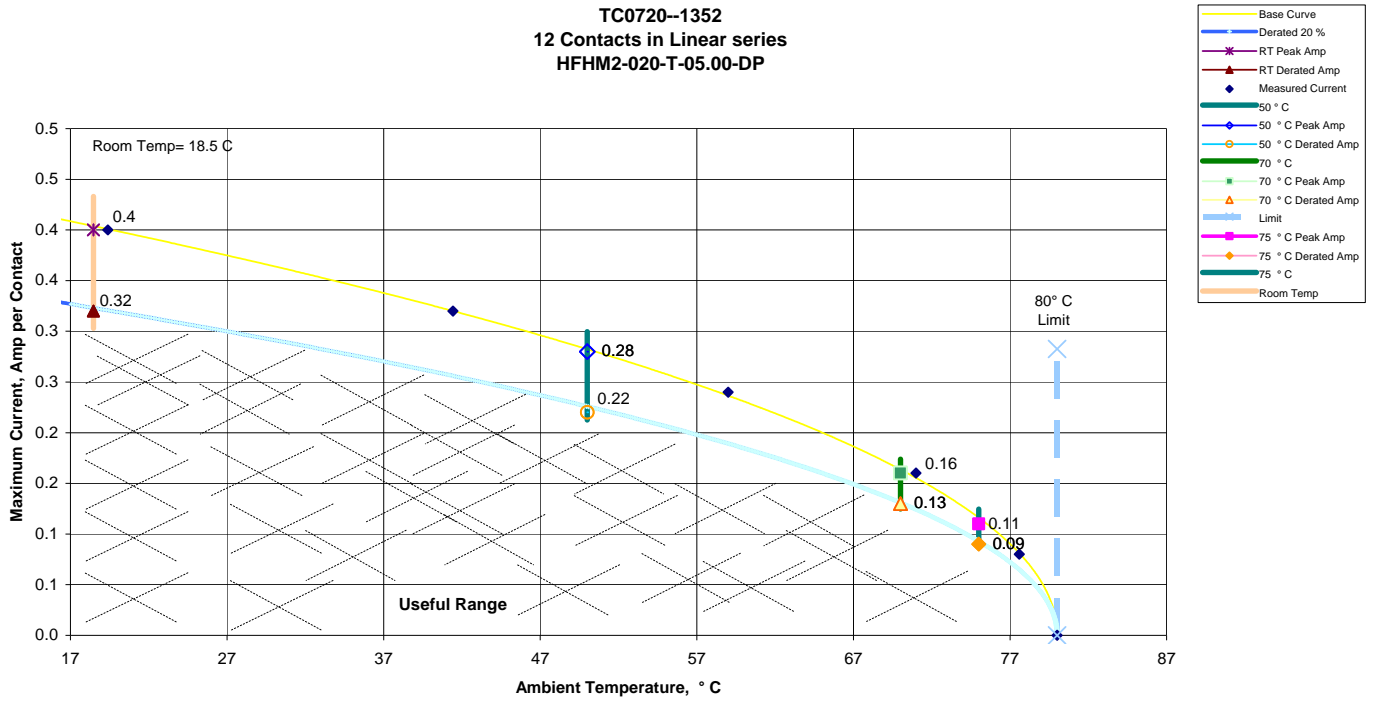
Temperature Rise, CCC at a 20% de-rating

- CCC for a 30°C Temperature Rise -----.31A per contact with 6 contacts powered in a Linear Series



Temperature Rise, CCC at a 20% de-rating

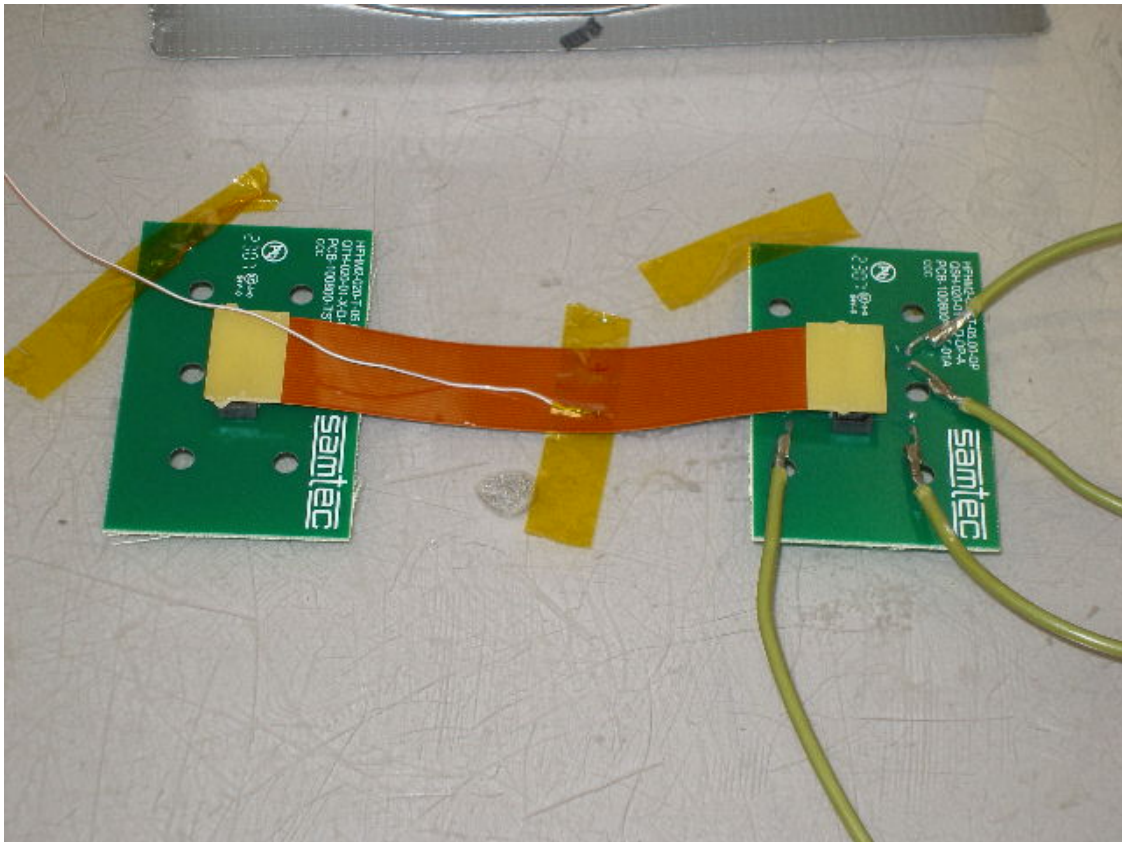
- CCC for a 30°C Temperature Rise -----.22A per contact with 12 contacts powered in a Linear Series



DATA SUMMARIES

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:
 - a. Linear configuration with six adjacent contacts powered
 - b. Linear configuration with twelve adjacent contacts powered



EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** PS-01**Description:** System Power Supply**Manufacturer:** Hewlett Packard**Model:** HP 6033A**Serial #:** (HP) 3329A-07330**Accuracy:** See Manual

... Last Cal: 06/22/07, Next Cal: 06/22/08

Equipment #: MO-02**Description:** Multimeter /Data Acquisition System**Manufacturer:** Keithley**Model:** 2700**Serial #:** 0780546**Accuracy:** See Manual

... Last Cal: 06/22/07, Next Cal: 06/22/08

Equipment #: TC111307-(001 - 017)**Description:** CCC Chamber Thermocouples**Manufacturer:** Samtec**Model:****Serial #:** TC111307-(001 - 017)**Accuracy:** +/- 1 Deg.

... Last Cal: 11/30/2007, Next Cal: 11/30/2008

... Last Cal: , Next Cal:

Equipment #: Null**Description:****Manufacturer:****Model:****Serial #:****Accuracy:**

... Last Cal: , Next Cal: